

Hermetic Schottky Diodes for Mixers and Detectors (1-18 GHz)

Technical Data

HSCH-6000 Series

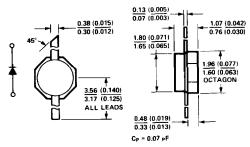
Features

- Low Parasitic Hermetic Package
 - -High Frequency Performance
- -Meets Performance Standards of Space Level Testing
- Lead Forming Option
 No Board Drilling Required
- Rugged Construction MIL-STD-750 Compliance
- High Uniformity
 Tightly Controlled Process
 Insures Consistent
 Performance
- Silicon Nitride Passivation, Tri-Metallization Stable High Temperature Performance

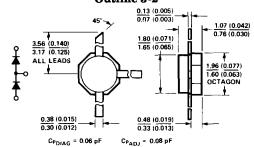
Description

These Schottky barrier diodes are fabricated by advanced epitaxial techniques. Precise process control insures uniformity and repeatability of this planar beam lead microwave semiconductor. A nitride passivation layer provides immunity from contaminants which could otherwise lead to I_R drift.

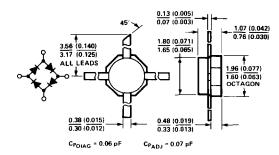
These diodes are packaged in the hermetic J package. Advanced design and assembly



Outline J-2



Outline J-3



Outline J-4
DIMENSIONS IN MILLIMETERS AND (INCHES)

processes minimize package parasitics resulting in optimum performance.

The body of the package is alumina, while the leads are gold-plated over nickel-plated Kovar. The solder glass seal and rugged construction meet the stringent requirements of space-level testing and are capable of meeting the environmental tests of MIL-STD-750.

Applications

These hermetic devices are designed for stripline and microstrip use. The design features extremely low package parasitics. The package outline also maximizes lead strength while reducing overall body size. This design is especially useful in environments requiring high frequency and/or wide band operation.

The single diode can be used in either mixer or detector applications. The pairs can be used in balanced mixers and can be configured to assemble bridge, star, and ring quads for Class I, II, or III type double balanced mixers. The quads are used as double balanced mixers, phase detectors, and AM and digital modulators.

Maximum Ratings

Pulse Power Incident at $T_{CASE} = 25^{\circ}C$	
(1 μs pulse, DC = 0.001)	1 W
CW Power Dissipation at $T_{CASE} = 25^{\circ}C$	
Derate Linearly to Zero at 175°C	150 mW/junction
Operating Temperature Range	65°C to +175°C
Storage Temperature Range	65°C to +200°C
Soldering Temperature	

These diodes are ESD sensitive. Handle with care to avoid static discharge through the diode.

Electrical Specifications at $T_{CASE} = 25^{\circ}C$ Single Diode in J-2 Package

Part Number HSCH-	Barrier	Maximum Noise Figure NF (dB)	Impe	F dance (Ω) Max.	Maximum SWR	Minimum Breakdown Voltage V _{BR} (V)	$\begin{array}{c} \textbf{Maximum} \\ \textbf{Dynamic} \\ \textbf{Resistance} \\ \textbf{R}_{\textbf{D}}\left(\Omega\right) \end{array}$	Maximum Forward Voltage V _F (mF)	Maximum Total Capacitance C _T (pF)
6310	Medium	7.2 at 16 GHz	200	400	1.5:1	4	16	500	0.22
6312		6.2 at 9.375 GHz					12	•	0.27
6330	Low	7.2 at 16 GHz	150	350			16	375	0.22
6332		6.2 at 9.375 GHz					12		0.27
Test Conditions		DC Load Res L.O. Power = $I_F = 30 \text{ MHz}$,	1 mW			I _R ≤ 10 μA	I _F = 5 mA	I _F = 1 mA	$V_{R} = 0 V$ $f = 1 MHz$

Diode Pairs in J-3 Package

Part Number HSCH-	Barrier	Max. Noise Figure NF (dB)	Impe	F dance (Ω) Max.	Max. SWR	Min. Breakdown Voltage V _{BR} (V)	$\begin{array}{c} \text{Max.} \\ \text{Dynamic} \\ \text{Resistance} \\ \text{R}_{\text{D}}\left(\Omega\right) \end{array}$	Max. ΔR _D (Ω)	Max. Total Capacitance C _T (pF)	Max. ΔC _T (pF)	Max. Forward Voltage V _F (mV)	Max. ΔV _p (mV)
6510	Medium	7.2 at 16 GHz	200	400	1.5:1	4	16	3	0.22	0.02	500	10
6512		6.2 at 9.375 GHz					12		0.27		· ·	
6530	Low	7.2 at 16 GHz	150	350] .	16		0.22		375	
6532		6.2 at 9.375 GHz					12		0.27			
Conditions L.O. Power		DC Load Resistance = 0Ω L.O. Power = 1 mW $I_B = 30 \text{ MHz}$, 1.5 dB NF				I _R ≤ 10 μA	I _F = 5 mA		V _R = 0 V f = 1 MHz		I _F = 1 mA	
					Measured between adjacent leads.							

Diode Quads in J-4 Package

Fre- quency Band	Part Number HSCH-	Barrier	Maximum Capacitance C _M (pF)	Maximum Measured Capacitance Difference ΔC _M (pF)	Maximum Dynamic Resistance R _D (Ω)	$\begin{array}{c} \text{Maximum} \\ \text{Resistance} \\ \text{Difference} \\ \Delta R_D\left(\Omega\right) \end{array}$	Maximum Forward Voltage V _y (mF)	Maximum V _F Difference ΔV _F (mV)
Ku	6810	Medium	0.22	0.03	20	3	500	15
$18\mathrm{GHz}$	6830	Low	1				375	
X	6812	Medium	0.27		16	2	500	
$12\mathrm{GHz}$	6832	Low	1				375	
1	Test Conditions		V _R = 0 V f = 1 MHz		$I_F = 5 \text{ mA}$		I _F = 1 mA	
					Measured between adjacent leads.			s.

Typical Parameters

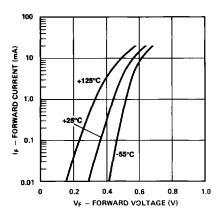


Figure 1. Typical Forward Characteristics for Medium Barrier Diodes.

Figure 2. Typical Forward Characteristics for Low Barrier Diodes.

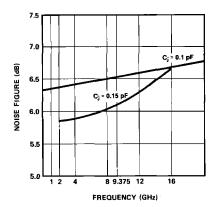


Figure 3. Typical Noise Figure vs. Frequency for J-Packages.

Typical Parameters (cont.)

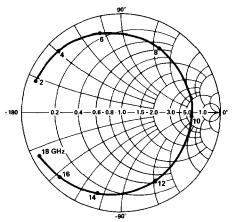


Figure 4. Typical Admittance Characteristics with 20 μA External Bias. HSCH-6310, -6330.

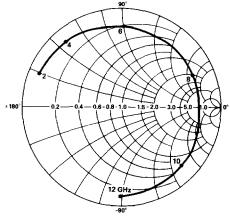
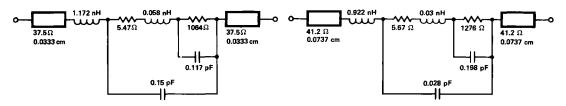


Figure 5. Typical Admittance Characteristics with 20 μA External Bias. HSCH-6312, -6332.

MODEL FOR J-2 PACKAGE SCHOTTKY DIODES AT 20 µA EXTERNAL BIAS HSCH-6310, -6330

MODEL FOR J-2 PACKAGE SCHOTTKY DIODES AT 20 µA EXTERNAL BIAS HSCH-6312, -6332



Special Order Information

In the event that mounting these diodes in the circuit requires leads formed as shown below, this lead configuration can be ordered directly. Please refer to the following table for order information.

